

## Features

- Uses CRM advanced Trench technology
- Extremely low on-resistance  $R_{DS(on)}$
- Excellent  $Q_g \times R_{DS(on)}$  product(FOM)
- Qualified according to JEDEC criteria

## Product Summary

$V_{DS}$	60V
$R_{DS(on)}$ typ.	16mΩ
$I_D$	10A

**100% DVDS Tested**

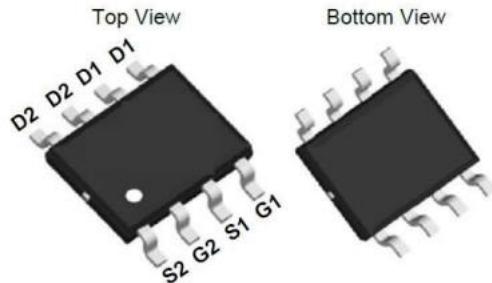
**100% Avalanche Tested**

## Applications

- Motor control and drive
- Electrical tools
- Lithium battery protection

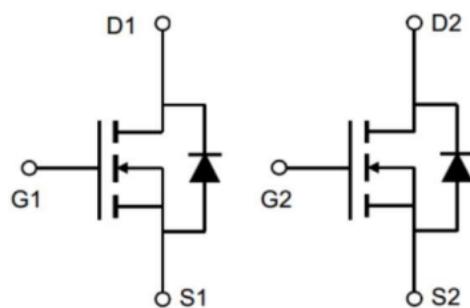


H F



**SOP-8(Dual)**

## Package Marking and Ordering Information



**Schematic Diagram**

Part #	Marking	Package	Packing	Reel Size	Tape Width	Qty
CRTE200N06L2D-G	T200N06L2D	SOP-8L	Reel	N/A	N/A	2500pcs

## Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	$V_{DS}$	60	V
Continuous drain current $T_A = 25^\circ C$	$I_D$	10	A
$T_A = 100^\circ C$		6.8	
Pulsed drain current ( $T_A = 25^\circ C$ , $t_p$ limited by $T_{jmax}$ )	$I_D$ pulse	40	A
Avalanche energy, single pulse ( $L=0.5mH$ )	$E_{AS}$	81	mJ
Gate-Source voltage	$V_{GS}$	$\pm 20$	V
Power dissipation ( $T_A = 25^\circ C$ )	$P_{tot}$	3.4	W
Operating junction and storage temperature	$T_j$ , $T_{stg}$	-55...+150	°C
Soldering temperature, wave soldering only allowed at leads (1.6mm from case for 10s)	$T_{sold}$	260	°C

**Thermal Resistance**

Parameter	Symbol	Typ	Max	Unit
Thermal resistance, junction – ambient(min. footprint)	R <sub>thJA</sub> <sup>a1</sup>	-	36.00	°C/W

**Electrical Characteristic (at T<sub>j</sub> = 25 °C, unless otherwise specified)**

Parameter	Symbol	Value			Unit	Test Condition
		min.	typ.	max.		

**Static Characteristic**

Drain-source breakdown voltage	BV <sub>DSS</sub>	-	-	60	V	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA
Gate threshold voltage	V <sub>GS(th)</sub>	1	1.5	2	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA
Zero gate voltage drain current	I <sub>DSS</sub>	-	-	1	µA	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V
		-	-	100		T <sub>j</sub> =25°C
		-	-			T <sub>j</sub> =150°C
Gate-source leakage current	I <sub>GSS</sub>	-	-	±100	nA	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V
Drain-source on-state resistance	R <sub>DS(on)</sub>		16	20	mΩ	T <sub>j</sub> =25°C
		-	19	25		V <sub>GS</sub> =10V, I <sub>D</sub> =6A
		-	-			V <sub>GS</sub> =4.5V, I <sub>D</sub> =5A
Transconductance	g <sub>fs</sub>	-	52.4	-	S	V <sub>DS</sub> =5V, I <sub>D</sub> =19A

**Dynamic Characteristic**

Input Capacitance	C <sub>iss</sub>	-	1688	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =30V f=1MHz
Output Capacitance	C <sub>oss</sub>	-	98	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	-	89	-		
Gate Total Charge	Q <sub>g</sub>	-	36.4	-	nC	V <sub>GS</sub> =10V, V <sub>DS</sub> =30V ID=6A, f=1MHz
Gate-Source charge	Q <sub>gs</sub>	-	5.15	-		
Gate-Drain charge	Q <sub>gd</sub>	-	9.05	-		
Turn-on delay time	t <sub>d(on)</sub>	-	11.8	-	ns	V <sub>GS</sub> =10V, V <sub>DS</sub> =30V RG=3Ω, RL=1.5Ω ID=6A
Rise time	t <sub>r</sub>	-	6.8	-		
Turn-off delay time	t <sub>d(off)</sub>	-	20	-		
Fall time	t <sub>f</sub>	-	10	-		
Gate resistance	R <sub>G</sub>	-	4.4	-	Ω	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V f=1MHz

**Body Diode Characteristic**

<b>Parameter</b>	<b>Symbol</b>	<b>Value</b>			<b>Unit</b>	<b>Test Condition</b>
		<b>min.</b>	<b>typ.</b>	<b>max.</b>		
Body Diode Forward Voltage	V <sub>SD</sub>	-	-	1.2	V	V <sub>GS</sub> =0V, I <sub>SD</sub> =6A
Body Diode Continuous Forward Current	I <sub>S</sub>	-	-	10	A	T <sub>C</sub> = 25°C
Body Diode Reverse Recovery Time	t <sub>rr</sub>	-	25.79	-	ns	I <sub>F</sub> =19A, dI/dt=100A/μs
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	-	19.57	-	nC	

a1: The value of R<sub>thJA</sub> is measured by placing the device in a still air box which is one cubic foot.

## Typical Performance Characteristics

Fig 1: Output Characteristics

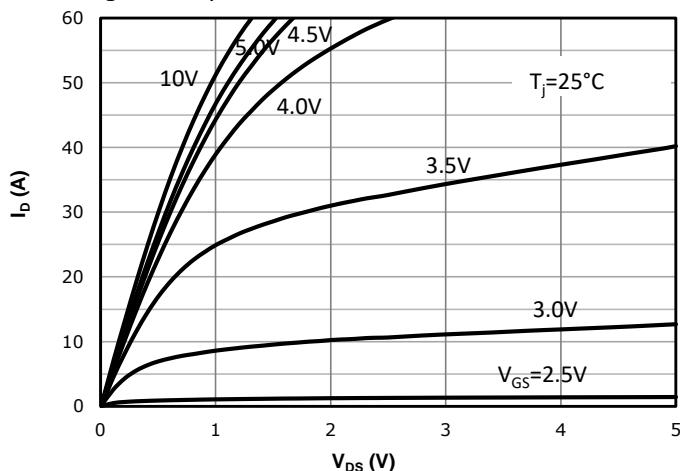


Fig 2: Transfer Characteristics

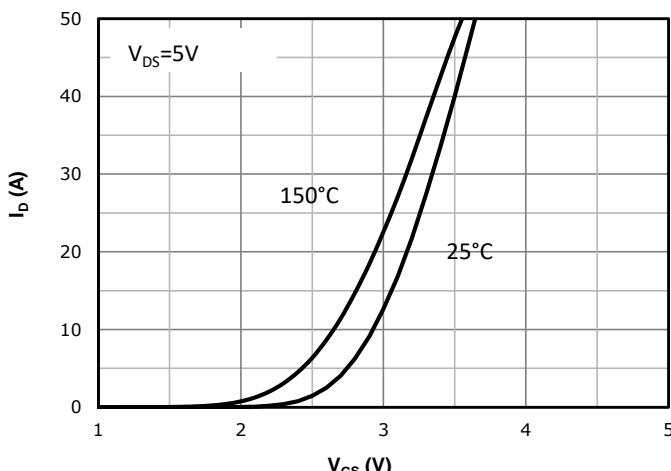


Fig 3:  $R_{DS(on)}$  vs Drain Current and Gate Voltage

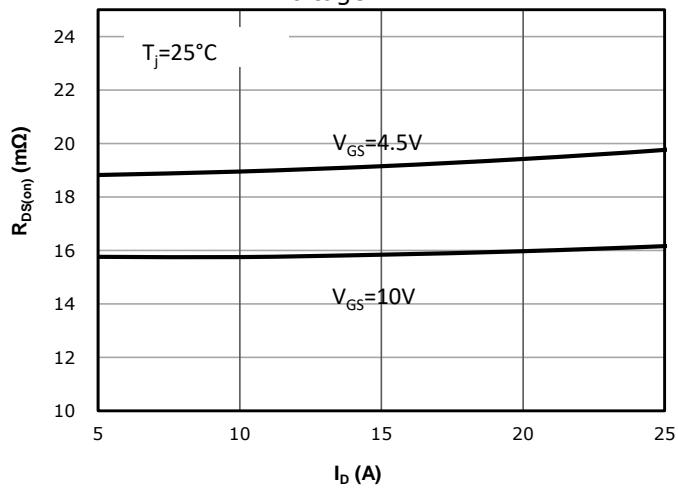


Fig 4:  $R_{DS(on)}$  vs Gate Voltage

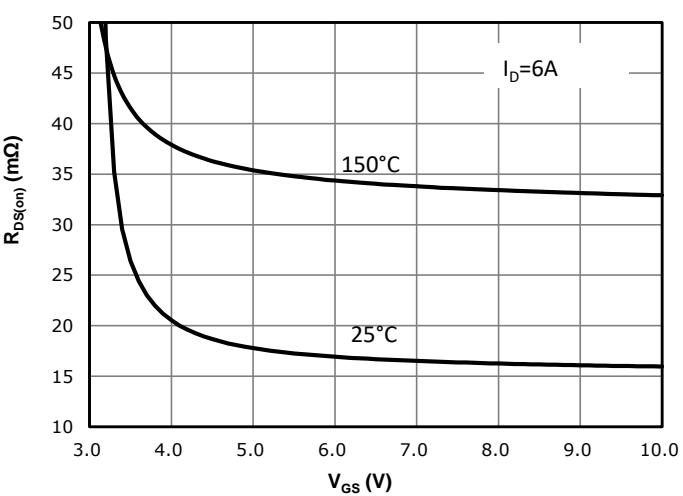


Fig 5:  $R_{DS(on)}$  vs. Temperature

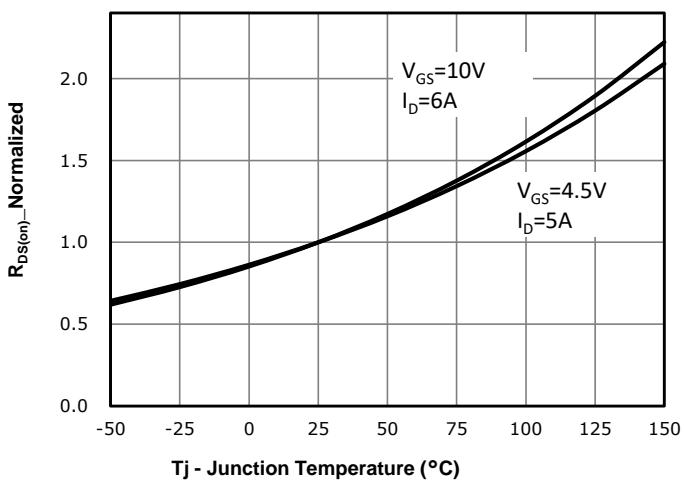
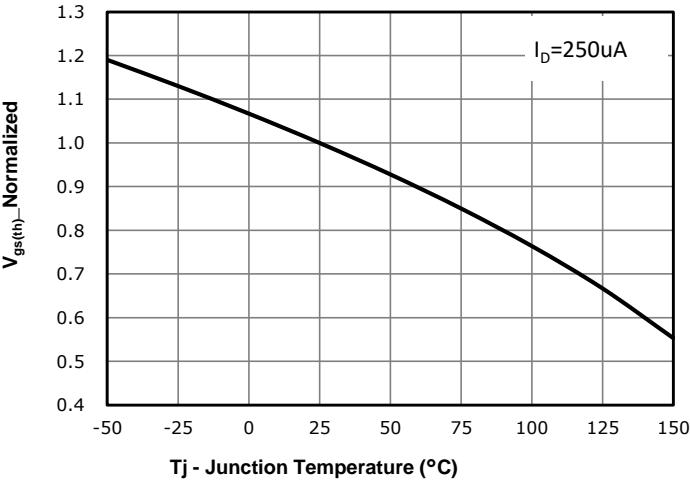


Fig 6:  $V_{GS(th)}$  vs. Temperature



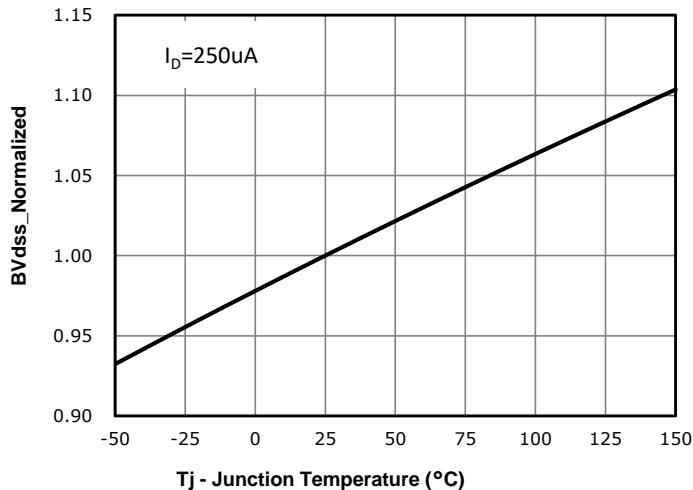
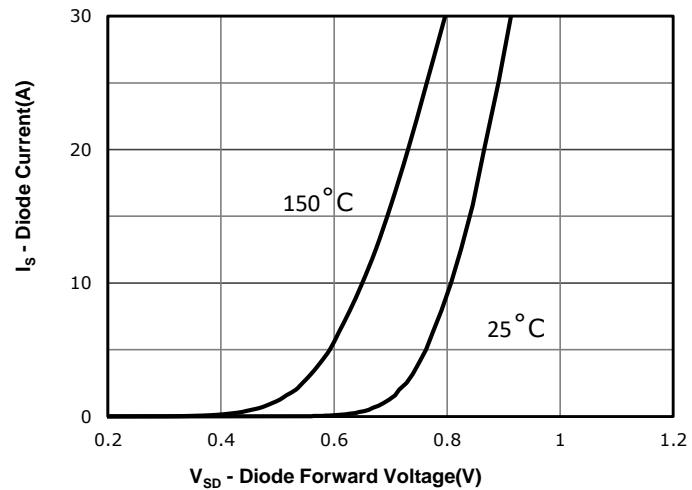
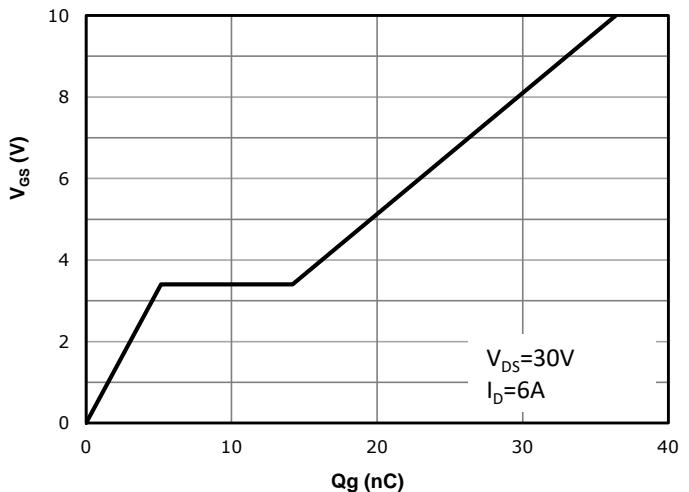
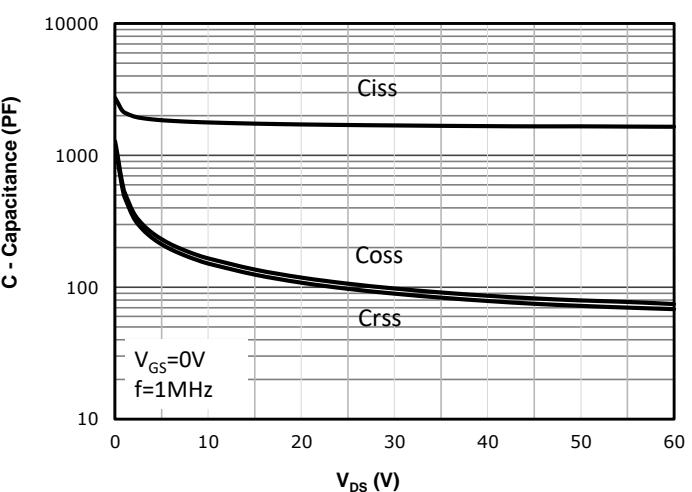
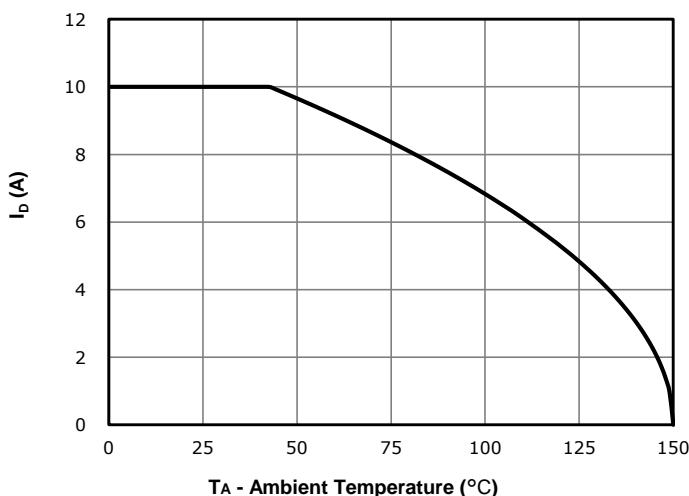
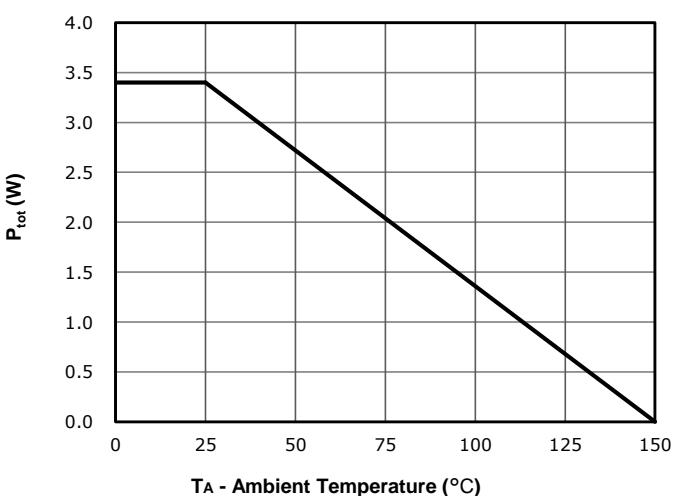
**Fig 7: BV<sub>dss</sub> vs. Temperature**

**Fig 8: Body-diode Forward Characteristics**

**Fig 9: Gate Charge Characteristics**

**Fig 10: Capacitance Characteristics**

**Fig 11: Drain Current Derating**

**Fig 12: Power Dissipation**


Fig 13: Safe Operating Area

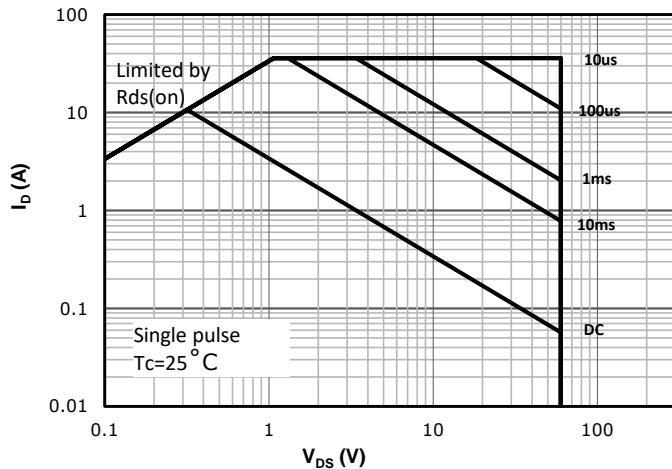
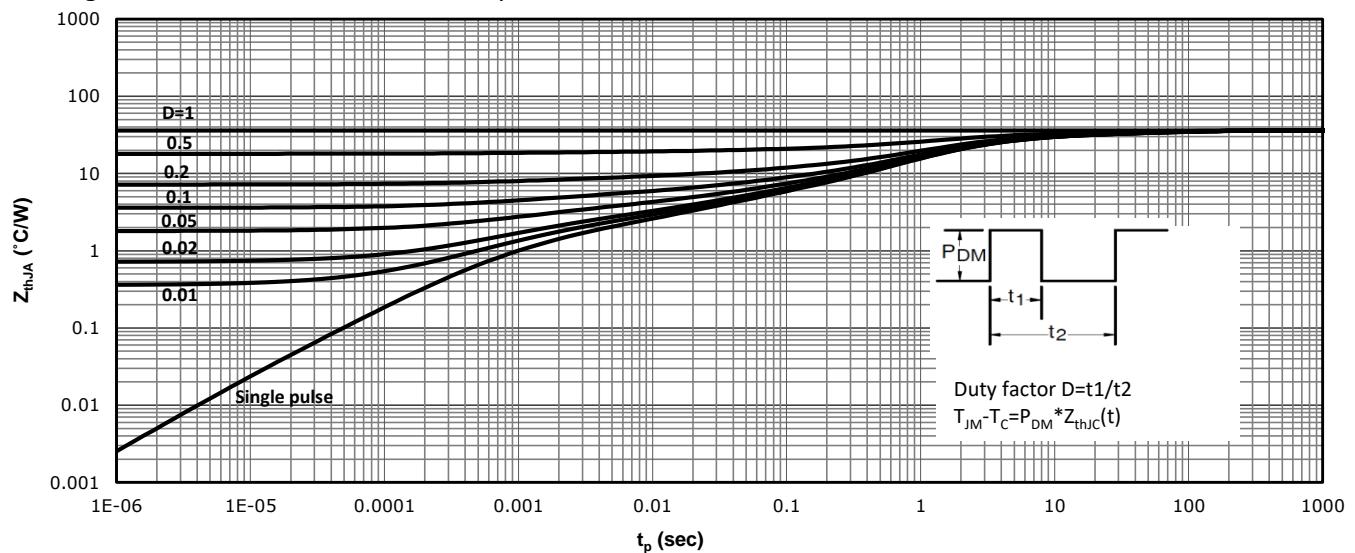
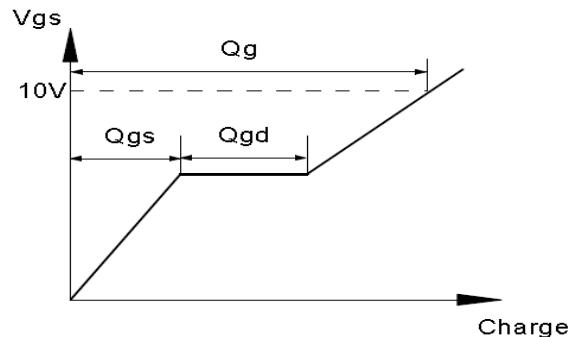
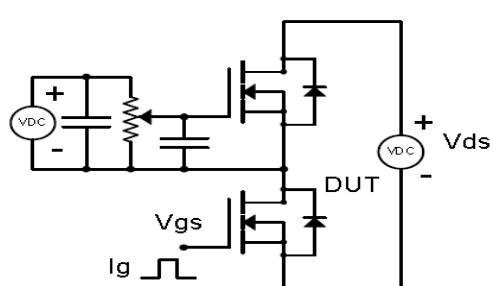


Fig 14: Max. Transient Thermal Impedance

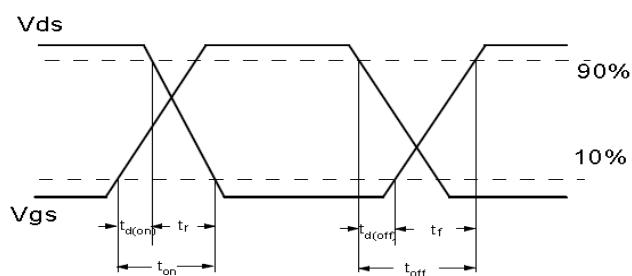
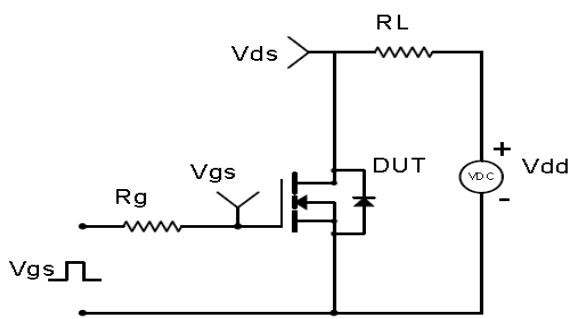


## Test Circuit & Waveform

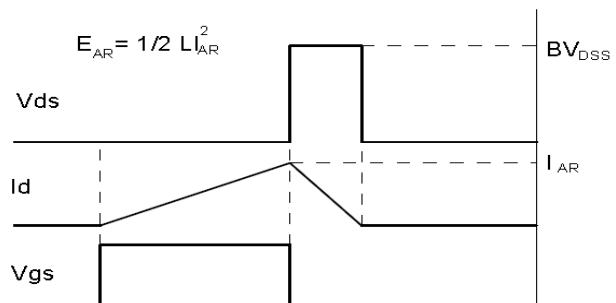
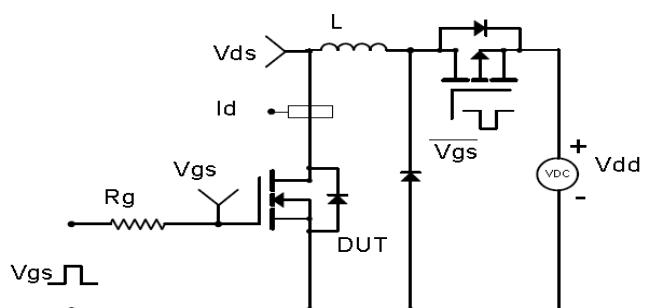
Gate Charge Test Circuit & Waveform



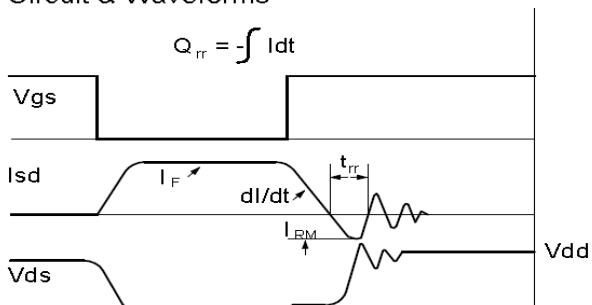
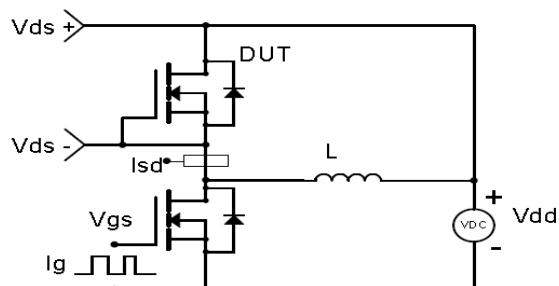
Resistive Switching Test Circuit & Waveforms

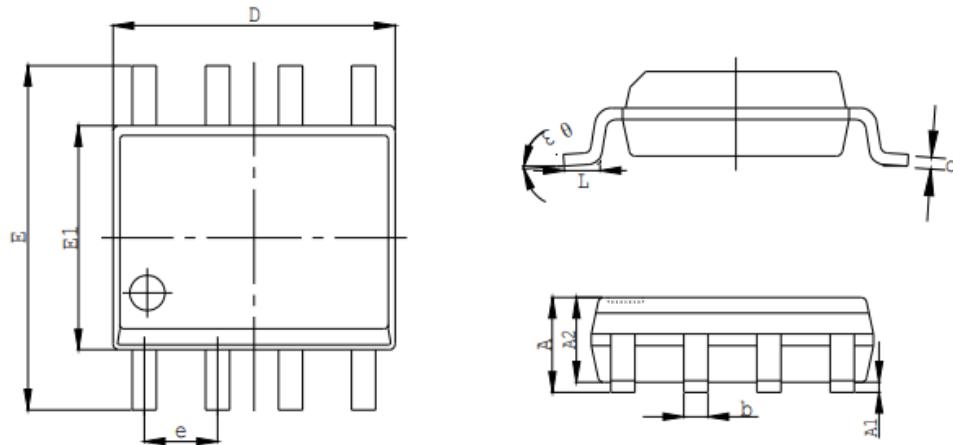


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

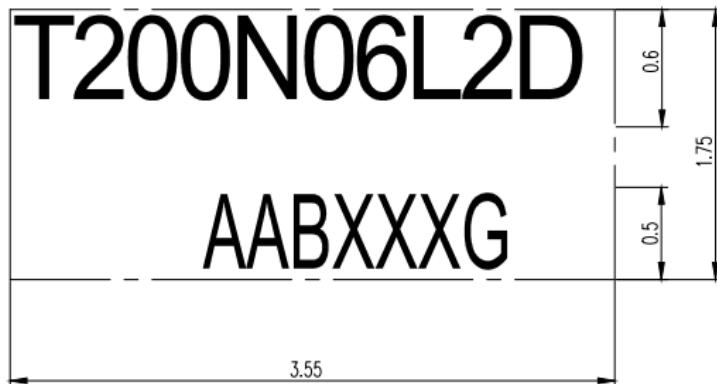


Diode Recovery Test Circuit & Waveforms



**Package Outline: SOP-8L**


Symbol	Values(mm)	
	Min.	Max.
A	1.30	1.80
A1	0.10	0.25
A2	1.30	1.50
E	5.80	6.20
E1	3.80	4.00
D	4.80	5.00
L	0.40	0.90
e	1.27TYP	
b	0.37	0.47
c	0.20TYP	
θ3	0°	8°

**Marking**

NOTE:  
AABXXXG  
AA      —cycle code  
B      —Fab code  
XXX    —Assembly lot code



## Revision History

Revison	Date	Major changes
1.0	2022/5/27	Relaease of formal version
2.0		
3.0		

## Disclaimer

Unless otherwise specified in the datasheet, the product is designed and qualified as a standard commercial product and is not intended for use in applications that require extraordinary levels of quality and reliability, such as automotive, aviation/aerospace and life-support devices or systems.

Any and all semiconductor products have certain probability to fail or malfunction, which may result in personal injury, death or property damage. Customer are solely responsible for providing adequate safe measures when design their systems.

CRM reserves the right to improve product design, function and reliability without notice.